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Nota di contenuto	ASMC 2012 proceedings produced by: semi [advertisement] -- Organizing Committee -- Corporate sponsors -- Table of contents -- Identifying systematic critical features using silicon diagnosis data -- Using selective voltage binning to maximize yield -- Analytic modeling of AC response to FET-level elements for CLY optimization -- Optimizing product yield using manufacturing defect weights -- Improving yield learning by electrical fault inspection -- Innovative approach to identify location of AMC source in cleanroom by inverse Computational Fluid Dynamics modeling -- Managing variability within wafertest production by combining lean and six sigma.